

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10092158	WIES ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Christopher Biagini	2445

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	203	10/8/2010	CDB

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Full-text search: US Patents, US Pubs., EPO, JPO, Derwent, IBM-TDB databases. See attached search history.	10/7/2010	CDB
Text-limited subclass search: 709/201-203,208-219,227-237,246-249; 345/156-184; 901/30-39; 715/200-210,234-242,700-702,733-749,760. See attached search history.	10/7/2010	CDB
Consulted with Primary Examiner Larry Donaghue (AU 2454).	10/6/2010	CDB
STIC patent and NPL search. See attached search strategies printout.	9/21/2010	CDB

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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